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LIST OF REFERENCES CITED BY APPLICANT (Use several sheets if necessary)					APPLICANT Benoist Sebire, et al.								
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if not in conformance and not considered. Include copy of this form with next communication to applicant.

Applicants: Benoist Sebire et al.  Filing Date: August 5, 2002 Group Art Unit: 2664  U.S. PATENT DOCUMENTS  Exam. Document Number Date Name Class Subclass Filing Date  FOREIGN PATENT DOCUMENTS  Exam Document Date Country Class Translation Filing	4
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Atty. Docket No.: Application Serial No.: 6173-4019US 09/937,949

Sheet 1 of 1

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BAN	JP 11-261519	09-1999	Japan	H04J	None
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Examiner: Binh Quoc Nguyen	Bonh	Date Considered:	08/3/05